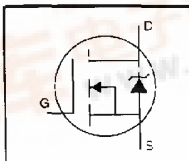


HEXFET® Power MOSFET

, 24小时加急出货

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement
- Enhanced 30V V_{GS} Rating
- Reduced C_{iss}, C_{oss}, Cr_{ss}
- Extremely High Frequency Operation
- Repetitive Avalanche Rated



$$V_{DSS} = 600V$$

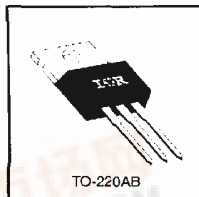
$$R_{DS(on)} = 1.2\Omega$$

$$I_D = 6.2A$$

Description

This new series of Low Charge HEXFETs achieve significantly lower gate charge over conventional MOSFETs. Utilizing the new LCDMOS technology, the device improvements are achieved without added product cost, allowing for reduced gate drive requirements and total system savings. In addition, reduced switching losses and improved efficiency are achievable in a variety of high frequency applications. Frequencies of a few MHz at high current are possible using the new Low Charge MOSFETs.

These device improvements combined with the proven ruggedness and reliability that are characteristic of HEXFETs offer the designer a new standard in power transistors for switching applications.



TO-220AB

Absolute Maximum Ratings

Parameter	Max.	Units
$I_C @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	6.2
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	3.9
I_{DM}	Pulsed Drain Current ⁽¹⁾	25
$P_D @ T_C = 25^\circ C$	Power Dissipation	125
	Linear Derating Factor	1.0
V_{GS}	Gate-to-Source Voltage	± 30
E_{AS}	Single Pulse Avalanche Energy ⁽²⁾	530
I_{AR}	Avalanche Current ⁽¹⁾	6.2
E_{AR}	Repetitive Avalanche Energy ⁽¹⁾	13
dv/dt	Peak Diode Recovery dv/dt ⁽³⁾	3.0
T_J	Operating Junction and Storage Temperature Range	-55 to +150
T_{SOL}	Soldering Temperature, for 10 seconds	300 (1.6mm from case)
	Mounting Torque, 6-32 or M3 screw	10 lbf-in (1.1 N-m)

Thermal Resistance

Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	1.0	$^\circ C/W$
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	—	0.50	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient	—	62	$^\circ C/W$


IRFBC40LC



Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V _{BR(DSS)}	Drain-to-Source Breakdown Voltage	600	—	—	V	V _{GS} =0V, I _D =250μA
ΔV _{BR(DSS)/ΔT_J}	Breakdown Voltage Temp. Coefficient	—	0.70	—	V/°C	Reference to 25°C, I _D =1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance	—	—	1.2	Ω	V _{GS} =10V, I _D =3.7A ④
V _{GS(th)}	Gate Threshold Voltage	2.0	—	4.0	V	V _{DS} =V _{GS} , I _D =250μA
g _{fs}	Forward Transconductance	3.7	—	—	S	V _{DS} =100V, I _D =3.7A ④
I _{DSS}	Drain-to-Source Leakage Current	—	—	100	μA	V _{DS} =600V, V _{GS} =0V
I _{DSS}	Gate-to-Source Forward Leakage	—	—	500	μA	V _{DS} =460V, V _{GS} =0V, T _J =125°C
I _{DSS}	Gate-to-Source Reverse Leakage	—	—	-100	nA	V _{GS} =20V
Q _g	Total Gate Charge	—	—	39	nC	I _D =6.2A
Q _{gs}	Gate-to-Source Charge	—	—	10	nC	V _{GS} =360V
Q _{gd}	Gate-to-Drain (Miller) Charge	—	—	19	nC	V _{GS} =10V See Fig. 6 and 13 ③
t _{di(on)}	Turn-On Delay Time	—	12	—	ns	V _{DD} =30CV
t _r	Rise Time	—	20	—	ns	I _D =6.2A
t _{d(off)}	Turn-Off Delay Time	—	27	—	ns	R _G =9.1Ω
t _f	Fall Time	—	17	—	ns	R _D =47Ω See Figure 10 ④
L _D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
L _S	Internal Source Inductance	—	7.5	—	nH	
C _{iss}	Input Capacitance	—	1100	—	pF	V _{GS} =0V
C _{oss}	Output Capacitance	—	140	—	pF	V _{DS} =25V
C _{rss}	Reverse Transfer Capacitance	—	15	—	pF	f=1.0MHz See Figure 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)	—	—	6.2	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I _{SM}	Pulsed Source Current (Body Diode) ①	—	—	25	A	
V _{SD}	Diode Forward Voltage	—	—	1.5	V	T _J =25°C, I _S =6.2A, V _{GS} =0V ④
t _r	Reverse Recovery Time	—	440	680	ns	T _J =25°C, I _F =6.2A
Q _{rr}	Reverse Recovery Charge	—	2.1	3.2	μC	dI/dt=100A/μs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ② V_{DD}=50V, starting T_J=25°C, L=25mH, R_G=25Ω, I_{AS}=6.2A (See Figure 12)
- ③ I_{SD}≤6.2A, dI/dt≤80A/μs, V_{DD}≤V_{BR(DSS)}, T_J≤150°C
- ④ Pulse width ≤ 300 μs; duty cycle ≤2%

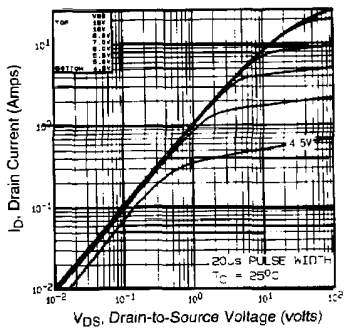


Fig 1. Typical Output Characteristics.
 $T_C = 25^\circ\text{C}$

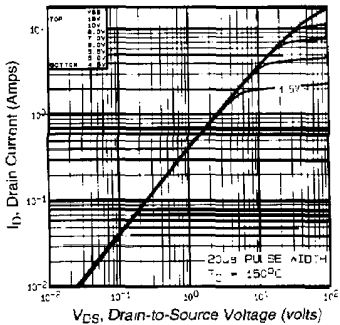


Fig 2. Typical Output Characteristics.
 $T_C = 150^\circ\text{C}$

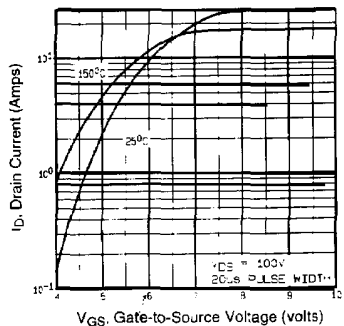


Fig 3. Typical Transfer Characteristics

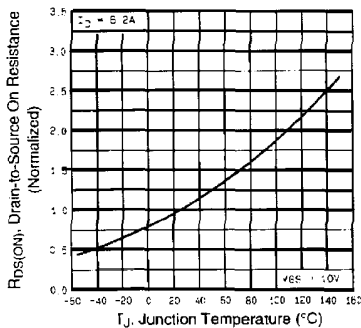


Fig 4. Normalized On-Resistance Vs. Temperature

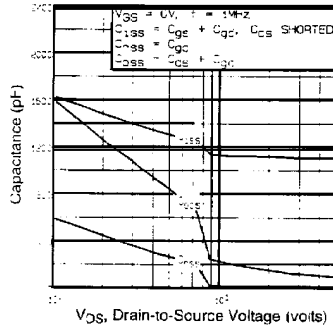


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

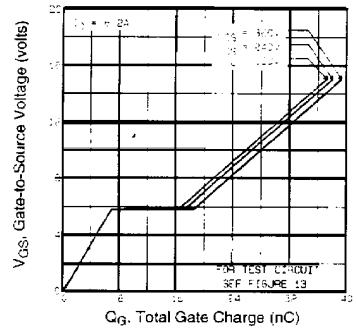


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

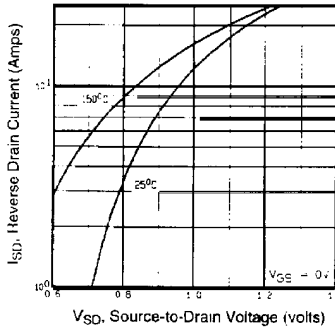


Fig 7. Typical Source-Drain Diode Forward Voltage

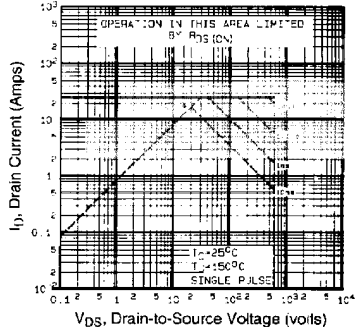


Fig 8. Maximum Safe Operating Area

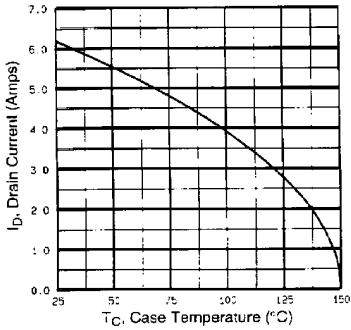


Fig 9. Maximum Drain Current Vs. Case Temperature

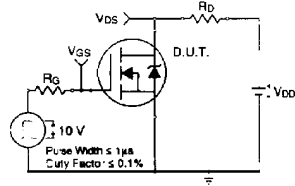


Fig 10a. Switching Time Test Circuit

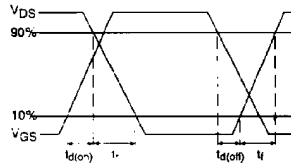


Fig 10b. Switching Time Waveforms

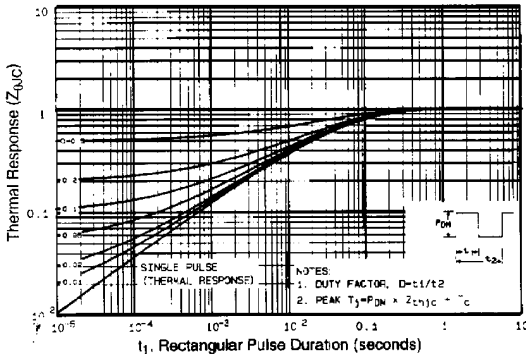


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

IRFBC40LC

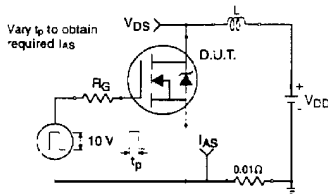


Fig 12a. Unclamped Inductive Test Circuit

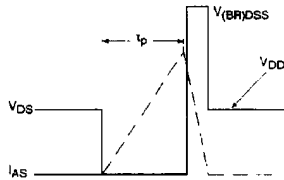


Fig 12b. Unclamped Inductive Waveforms

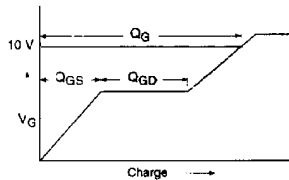


Fig 13a. Basic Gate Charge Waveform

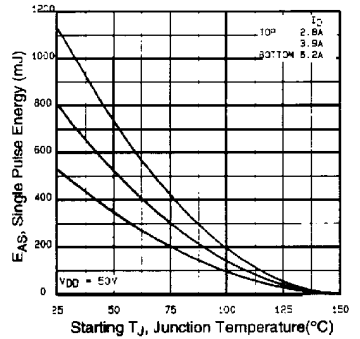


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

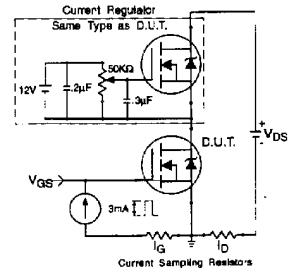


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit

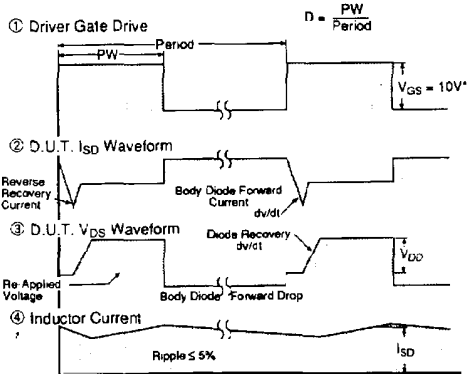
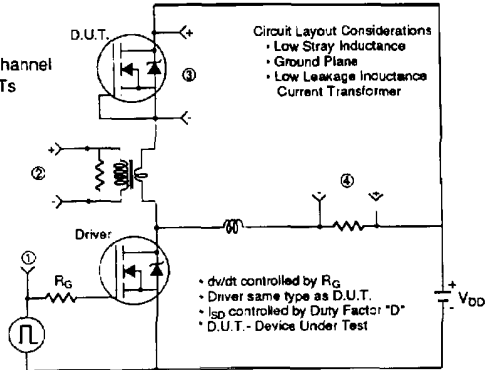
Appendix B: Package Outline Mechanical Drawing

Appendix C: Part Marking Information

Appendix A

Peak Diode Recovery dv/dt Test Circuit

Fig 14. For N-Channel HEXFETs



* $V_{GS} = 5V$ for Log c Level Devices

IRFBC40LC

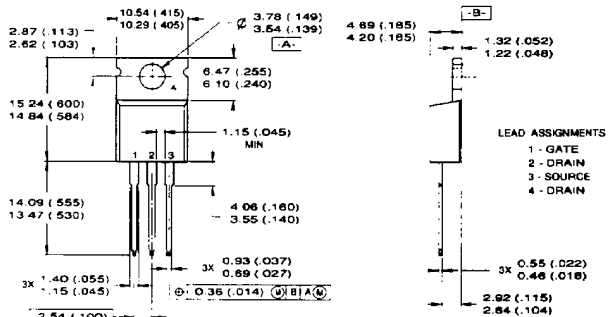


Package Outline

Appendix B

TO-220AB Outline

Dimensions are shown in millimeters (inches)



LEAD ASSIGNMENTS

- 1 - GATE
- 2 - DRAIN
- 3 - SOURCE
- 4 - DRAIN

NOTES:

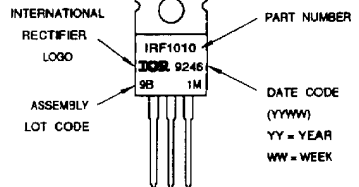
- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M 1982
- 2 CONTROLLING DIMENSION INCH
- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220-AB
- 4 HEATSIK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

Part Marking Information

Appendix C

TO-220AB

EXAMPLE: THIS IS AN IRF1010 WITH
ASSEMBLY LOT CODE 9B1M



Printed on Signal recycled offset:
made from 50% recycled waste paper including
10% de-inked, post-consumer waste.



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IR Rectifier

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EUROPEAN HEADQUARTERS: Hurst Green, Oxind, Surrey RH6 9BB England, Tel: (0883) 713215, Fax: 95219

IR CANADA: 101 Bertley St., Markham Ontario L3R 3L1, Tel: (416) 475-1897 IR GERMANY: Seeburgerstrasse 57, D-6390 Bad Homburg, Tel: 6172-37066 IR ITALY: Via Liguria 49
10071 Borgaro, Torino, Tel: (011) 410 1484 IR PAK SAUDI: KAN Bulking, 30-4 Haniyatubukuro 3-Chome, Tahme-ku, Tokyo 171 Japan, Tel: (03) 963 0641 IR SOUTHEAST ASIA:
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